

**RADIATION HARDENED  
 NPN LOW POWER SILICON TRANSISTOR**  
*Qualified per MIL-PRF-19500/368*

**DEVICES**

<b>2N3439</b>	<b>2N3440</b>
<b>2N3439L</b>	<b>2N3440L</b>
<b>2N3439UA</b>	<b>2N3440UA</b>

**LEVELS**

**JANSM – 3K Rads (Si)**  
**JANSJ – 10K Rads (Si)**  
**JANSP – 30K Rads (Si)**  
**JANSL – 50K Rads (Si)**  
**JANSR – 100K Rads (Si)**

**ABSOLUTE MAXIMUM RATINGS** ( $T_C = +25^\circ\text{C}$  unless otherwise noted)

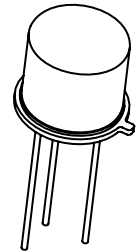
Parameters / Test Conditions	Symbol	2N3439	2N3440	Unit
Collector-Emitter Voltage	$V_{CEO}$	350	250	Vdc
Collector-Base Voltage	$V_{CBO}$	450	300	Vdc
Emitter-Base Voltage	$V_{EBO}$	7.0		Vdc
Collector Current	$I_C$	1.0		A dc
Total Power Dissipation	$P_T$	@ $T_A = +25^\circ\text{C}$ <sup>(1)</sup>		W
UA		@ $T_C = +25^\circ\text{C}$ <sup>(2)</sup>		
		@ $T_{SP} = +25^\circ\text{C}$ <sup>(3)</sup>		
Operating & Storage Temperature Range	$T_{op}, T_{stg}$	-65 to +200		$^\circ\text{C}$

**NOTES:**

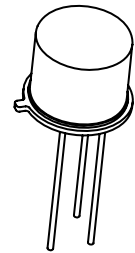
- 1) Derate linearly @ 4.57mW/ $^\circ\text{C}$  for  $T_A > +25^\circ\text{C}$
- 2) Derate linearly @ 28.5mW/ $^\circ\text{C}$  for  $T_C > +25^\circ\text{C}$
- 3) Derate linearly @ 14mW/ $^\circ\text{C}$  for  $T_{SP} > +25^\circ\text{C}$

**ELECTRICAL CHARACTERISTICS** ( $T_A = +25^\circ\text{C}$ , unless otherwise noted)

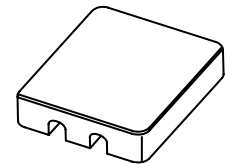
Parameters / Test Conditions	Symbol	Min.	Max.	Unit
<b>OFF CHARACTERISTICS</b>				
Collector-Emitter Breakdown Voltage $I_C = 10\text{mA dc}$ $R_{BB1} = 470\Omega; V_{BB1} = 6\text{V}$ $L = 25\text{mH (min)}; f = 30 - 60\text{Hz}$	$V_{(BR)CEO}$	350	250	Vdc
Collector-Emitter Cutoff Current $V_{CE} = 300\text{Vdc}$ $V_{CE} = 200\text{Vdc}$	$I_{CEO}$		2.0 2.0	$\mu\text{A dc}$
Emitter-Base Cutoff Current $V_{EB} = 7.0\text{Vdc}$	$I_{EBO}$		10	$\mu\text{A dc}$
Collector-Emitter Cutoff Current $V_{CE} = 450\text{Vdc}, V_{BE} = -1.5\text{Vdc}$ $V_{CE} = 300\text{Vdc}, V_{BE} = -1.5\text{Vdc}$	$I_{CEX}$		5.0 5.0	$\mu\text{A dc}$
Collector-Base Cutoff Current $V_{CB} = 360\text{Vdc}$ $V_{CB} = 250\text{Vdc}$ $V_{CB} = 450\text{Vdc}$ $V_{CB} = 300\text{Vdc}$	$I_{CBO}$		2.0 2.0 5.0 5.0	$\mu\text{A dc}$



**TO-5**  
**2N3439L, 2N3440L**



**TO-39 (TO-205AD)**  
**2N3439, 2N3440**



**UA**  
**2N3439UA, 2N3440UA**

## ELECTRICAL CHARACTERISTICS ( $T_A = +25^\circ\text{C}$ , unless otherwise noted) (CONT.)

Parameters / Test Conditions	Symbol	Min.	Max.	Unit
<b>ON CHARACTERISTICS</b> <sup>(3)</sup>				
Forward-Current Transfer Ratio $I_C = 20\text{mA}$ , $V_{CE} = 10\text{Vdc}$ $I_C = 2.0\text{mA}$ , $V_{CE} = 10\text{Vdc}$ $I_C = 0.2\text{mA}$ , $V_{CE} = 10\text{Vdc}$	$h_{FE}$	40 30 10	160	
Collector-Emitter Saturation Voltage $I_C = 50\text{mA}$ , $I_B = 4.0\text{mA}$	$V_{CE(sat)}$		0.5	Vdc
Base-Emitter Saturation Voltage $I_C = 50\text{mA}$ , $I_B = 4.0\text{mA}$	$V_{BE(sat)}$		1.3	Vdc

## DYNAMIC CHARACTERISTICS

Parameters / Test Conditions	Symbol	Min.	Max.	Unit
Magnitude of Common Emitter Small-Signal Short-Circuit Forward Current Transfer Ratio $I_C = 10\text{mA}$ , $V_{CE} = 10\text{Vdc}$ , $f = 5.0\text{MHz}$	$ h_{fe} $	3.0	15	
Forward Current Transfer Ratio $I_C = 5.0\text{mA}$ , $V_{CE} = 10\text{V}$ , $f = 1.0\text{kHz}$	$h_{fe}$	25		
Output Capacitance $V_{CB} = 10\text{Vdc}$ , $I_E = 0$ , $100\text{kHz} \leq f \leq 1.0\text{MHz}$	$C_{obo}$		10	pF
Input Capacitance $V_{CB} = 5.0\text{Vdc}$ , $I_E = 0$ , $100\text{kHz} \leq f \leq 1.0\text{MHz}$	$C_{ibo}$		75	pF

## SWITCHING CHARACTERISTICS

Parameters / Test Conditions	Symbol	Min.	Max.	Unit
Turn-On Time $V_{CC} = 200\text{Vdc}$ ; $I_C = 20\text{mA}$ , $I_{B1} = 2.0\text{mA}$	$t_{on}$		1.0	$\mu\text{s}$
Turn-Off Time $V_{CC} = 200\text{Vdc}$ ; $I_C = 20\text{mA}$ , $I_{B1} = -I_{B2} = 2.0\text{mA}$	$t_{off}$		10	$\mu\text{s}$

## SAFE OPERATING AREA

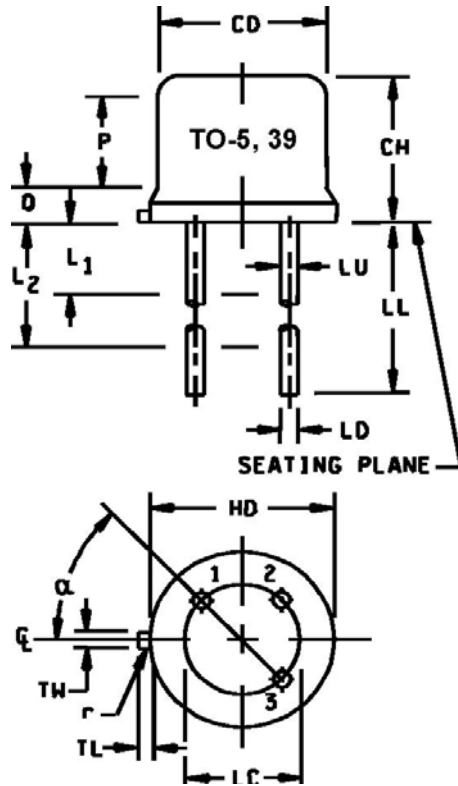
<b>DC Tests</b>	
$T_C = +25^\circ\text{C}$ , 1 Cycle, $t = 1.0\text{s}$	
<b>Test 1</b>	
$V_{CE} = 5.0\text{Vdc}$ , $I_C = 1.0\text{A}$	Both Types
<b>Test 2</b>	
$V_{CE} = 350\text{Vdc}$ , $I_C = 14\text{mA}$	2N3439 / L / UA
<b>Test 3</b>	
$V_{CE} = 250\text{Vdc}$ , $I_C = 20\text{mA}$	2N3440 / L / UA

(3) Pulse Test: Pulse Width =  $300\mu\text{s}$ , Duty Cycle  $\leq 2.0\%$

## POST RADIATION ELECTRICAL CHARACTERISTICS

Parameters / Test Conditions	Symbol	Min.	Max.	Unit
Collector-Emitter Cutoff Current $V_{CE} = 300\text{Vdc}$ $V_{CE} = 200\text{Vdc}$ 2N3439 / L / UA 2N3440 / L / UA	$I_{CEO}$		4 4	$\mu\text{A dc}$
Emitter-Base Cutoff Current $V_{EB} = 7.0\text{Vdc}$	$I_{EBO}$		20	$\mu\text{A dc}$
Collector-Emitter Cutoff Current $V_{CE} = 450\text{Vdc}$ , $V_{BE} = -1.5\text{Vdc}$ $V_{CE} = 300\text{Vdc}$ , $V_{BE} = -1.5\text{Vdc}$ 2N3439 / L / UA 2N3440 / L / UA	$I_{CEX}$		10 10	$\mu\text{A dc}$
Collector-Base Cutoff Current $V_{CB} = 360\text{Vdc}$ $V_{CB} = 250\text{Vdc}$ $V_{CB} = 450\text{Vdc}$ $V_{CB} = 300\text{Vdc}$ 2N3439 / L / UA 2N3440 / L / UA 2N3439 / L / UA 2N3440 / L / UA	$I_{CBO}$		4 4 10 10	$\mu\text{A dc}$
Forward-Current Transfer Ratio $I_C = 20\text{mA dc}$ , $V_{CE} = 10\text{Vdc}$ $I_C = 2.0\text{mA dc}$ , $V_{CE} = 10\text{Vdc}$ $I_C = 0.2\text{mA dc}$ , $V_{CE} = 10\text{Vdc}$	$[h_{FE}]$	[20] [15] [5]	160	
Collector-Emitter Saturation Voltage $I_C = 50\text{mA dc}$ , $I_B = 4.0\text{mA dc}$	$V_{CE(sat)}$		0.56	Vdc
Base-Emitter Saturation Voltage $I_C = 50\text{mA dc}$ , $I_B = 4.0\text{mA dc}$	$V_{BE(sat)}$		1.5	Vdc

## PACKAGE DIMENSIONS



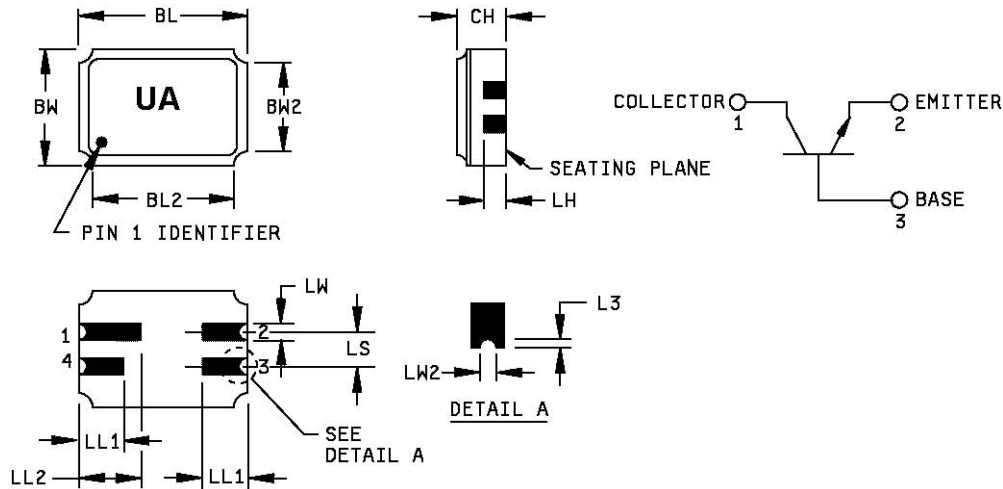
Symbol	Dimensions				Note
	Inches		Millimeters		
	Min	Max	Min	Max	
CD	.305	.335	7.75	8.51	6
CH	.240	.260	6.10	6.60	
HD	.335	.370	8.51	9.40	
LC	.200 TP		5.08 TP		7
LD	.016	.019	0.41	0.48	8,9
LL	See note 14				
LU	.016	.019	0.41	0.48	8,9
L1		.050		1.27	8,9
L2	.250		6.35		8,9
P	.100		2.54		7
Q		.030		0.76	5
TL	.029	.045	0.74	1.14	3,4
TW	.028	.034	0.71	0.86	3
r		.010		0.25	10
$\alpha$	45° TP		45° TP		7

### NOTES:

- Dimensions are in inches.
- Millimeters are given for general information only.
- Beyond r (radius) maximum, TW shall be held for a minimum length of .011 (0.28 mm).
- Dimension TL measured from maximum HD.
- Body contour optional within zone defined by HD, CD, and Q.
- CD shall not vary more than .010 inch (0.25 mm) in zone P. This zone is controlled for automatic handling.
- Leads at gauge plane  $.054 + .001 - .000$  inch ( $1.37 + 0.03 - 0.00$  mm) below seating plane shall be within .007 inch (0.18 mm) radius of true position (TP) at maximum material condition (MMC) relative to tab at MMC. The device may be measured by direct methods or by gauging procedure.
- Dimension LU applies between L1 and L2. Dimension LD applies between L2 and LL minimum. Diameter is uncontrolled in and beyond LL minimum.
- All three leads.
- The collector shall be internally connected to the case.
- Dimension r (radius) applies to both inside corners of tab.
- In accordance with ASME Y14.5M, diameters are equivalent to  $\Phi x$  symbology.
- Lead 1 = emitter, lead 2 = base, lead 3 = collector.
- For transistor types 2N3439L and 2N3440L (T0-5), dimension LL = 1.5 inches (38.10 mm) min. and 1.75 inches (44.45 mm) max. For transistor types 2N3439 and 2N3440 (T0-39), dimension LL = .5 inch (12.70 mm) min. and .750 inch (19.05 mm) max.

**FIGURE 1.** Physical dimensions (similar to TO-5 and TO-39).

## PACKAGE DIMENSIONS



### NOTES:

1. Dimensions are in inches.
2. Millimeters are given for general information only.
3. Dimension "CH" controls the overall package thickness. When a window lid is used, dimension "CH" must increase by a minimum of .010 inch (0.254 mm) and a maximum of .040 inch (1.020 mm).
4. The corner shape (square, notch, radius, etc.) may vary at the manufacturer's option, from that shown on the drawing.
5. Dimensions "LW2" minimum and "L3" minimum and the appropriate castellation length define an unobstructed three-dimensional space traversing all of the ceramic layers in which a castellation was designed. (Castellations are required on bottom two layers, optional on top ceramic layer.) Dimension "LW2" maximum and "L3" maximum define the maximum width and depth of the castellation at any point on its surface. Measurement of these dimensions may be made prior to solder dipping.
6. The coplanarity deviation of all terminal contact points, as defined by the device seating plane, shall not exceed .006 inch (0.15mm) for solder dipped leadless chip carriers.
7. In accordance with ASME Y14.5M, diameters are equivalent to  $\phi x$  symbology.

Symbol	Dimensions				Note
	Inches		Millimeters		
	Min	Max	Min	Max	
BL	.215	.225	5.46	5.71	
BL2		.225		5.71	
BW	.145	.155	3.68	3.93	
BW2		.155		3.93	
CH	.061	.075	1.55	1.90	3
L3	.003	.007	0.08	0.18	5
LH	.029	.042	0.74	1.07	
LL1	.032	.048	0.81	1.22	
LL2	.072	.088	1.83	2.23	
LS	.045	.055	1.14	1.39	
LW	.022	.028	0.56	0.71	
LW2	.006	.022	0.15	0.56	5

Pin no.	1	2	3	4
Transistor	Collector	Emitter	Base	N/C

**FIGURE 2.** Physical dimensions, surface mount (2N3439UA, 2N3440UA) version.